

Lecture #6

Semiconductors in EQ (cont.)

→ once doped, s.c. is now "extrinsic"

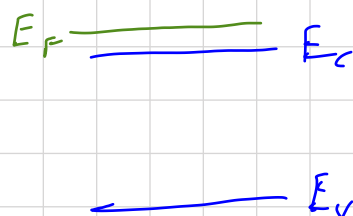
→ Ionization energy is the E to ionize the dopants
 ~ for Si, this is $\sim kT$

→ It turns out that the product $n_0 p_0$ in an extrinsic S.C. is: $n_0 p_0 = N_c N_v \exp\left[\frac{-E_g}{kT}\right]$

$\therefore n_0 p_0 = n_i^2$ ★ considered a material parameter for a given T

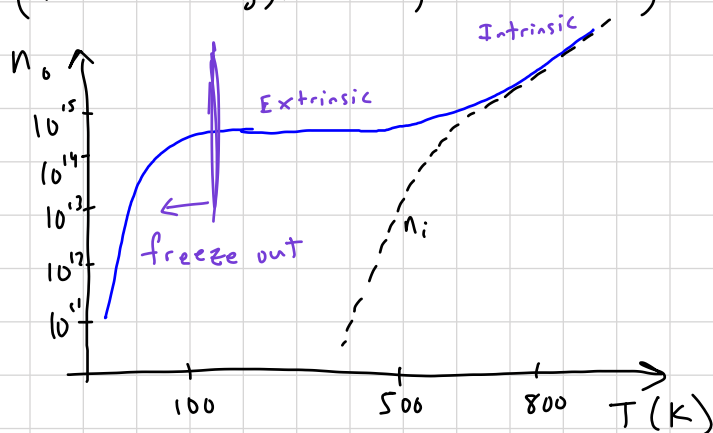
★ Same as for intrinsic!

→ If E_F is within E_c or $E_v \equiv$ degenerate S.C.



n-type degenerately doped S.C., Boltzmann Approx. does not apply!

→ Temperature (thermal energy) is key to ionizing dopants:



→ E_F position will depend on temperature and doping concentration, N_d / N_a

$$E_c - E_F = kT \ln\left(\frac{N_c}{n_0}\right) = kT \ln\left(\frac{N_c}{N_d}\right)$$

→ Thermal EQ
 → nondegenerate
 → n-type

when $N_d \gg n_i$

donor dopant conc.

acceptor dopant conc.

Charge Neutrality — in thermal EQ, S.C. is electrically neutral \equiv net charge densit = 0

$$n_0 + \underbrace{N_a^-}_{\text{ionized acceptors}} = p_0 + \underbrace{N_d^+}_{\text{ionized donors}}$$

assume complete ionization of all dopants

$$n_0 p_0 = n_i^2$$

$$n_0 + N_a = \frac{n_i^2}{n_0} + N_d$$

$$n_0^2 - (N_d - N_a)n_0 - n_i^2 = 0$$



$$n_o = \frac{(N_d - N_a)}{2} + \sqrt{\left(\frac{N_d - N_a}{2}\right)^2 + n_i^2}$$

$$p_o = \left(\frac{N_a - N_d}{2}\right) + \sqrt{\left(\frac{N_a - N_d}{2}\right)^2 + n_i^2}$$

→ Thermal EQ

→ full ionization

general case solutions

Special Cases

(1) Intrinsic S.C. ($N_a = 0, N_d = 0$)

$$n_o = n_i, p_o = n_i$$

(2) Doped, nondegenerate S.C. with either: $N_d - N_a \approx N_d \gg n_i$ or $N_a - N_d \approx N_a \gg n_i$

→ most typical case found in devices

$$n_o \approx N_d$$

$$p_o \approx N_a$$

$$p_o = \frac{n_i^2}{N_d}$$

or

$$n_o \approx \frac{n_i^2}{N_a}$$

(3) Doped S.C. with $n_i \gg |N_d - N_a|$ — "lightly doped"

→ at reasonable temperatures, n_i will exceed N_d or N_a

$$n_o = p_o = n_i$$

(4) Compensated S.C. where N_a and N_d are comparable and nonzero ($N_a - N_d \approx 0$)

→ use full expressions for n_o, p_o

(5) S.C. at very high temp, $n_i \gg |N_a - N_d|$

$$n_o \approx p_o \approx n_i$$

Carrier Transport - Drift

Review of some basic electrical behaviors:

voltage (V), current (A), $Amp = \frac{C}{s}$

Ohm's Law: $V = IR$ — resistance (Ω)

Current density: $J = \frac{I}{A} \left(\frac{A}{cm^2} \right) = \sigma E$
electric field
conductivity

electric field: $E = \frac{V}{L} \left(\frac{V}{cm} \right)$

resistivity: $\rho = \frac{RA}{L} \left(\Omega \cdot cm \right)$ or $R = \frac{\rho L}{A}$

conductivity: $\sigma = \frac{1}{\rho} \left(\frac{S}{cm} \right)$

★ Direction of current flow:

- h^+ go with E -field, hence J_p goes with E

- e^- go against E -field, but J_n still goes with E

★ it's a convention!

Drift current — charged carrier motion due to an applied E -field

→ Last time we deduced how to determine # of e^- (n_0) and h^+ (p_0) and now need to see how they move when an E -field is applied

negative because
 e^- are neg.
carriers

e^- current

$$J_{n|drift} = -e n_0 v_{dn}$$

average drift
velocity

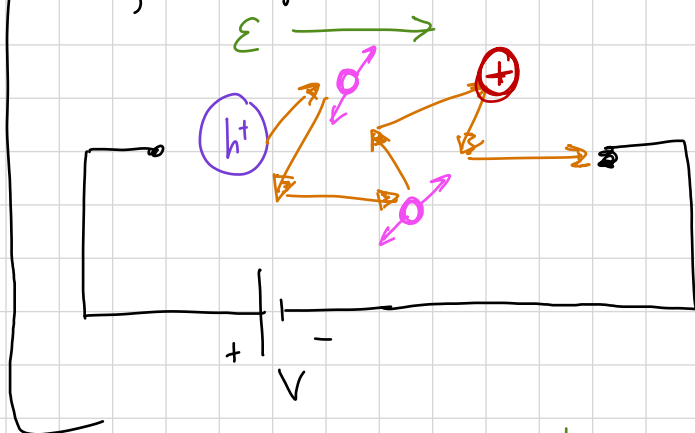
h^+ current

$$J_{p|drift} = e p_0 v_{dp}$$

elementary charge (q)

side
note

Why "average" drift velocity?



e^- mobility

$$v_{dn} = -\mu_n E$$

★ Carriers will scatter as they are accelerated by applied E -field:

Lattice scattering: Thermal energy ($T > 0K$) causes lattice atoms to vibrate, disrupting potential profile and scattering carriers.

Impurity scattering: ionized impurities disrupt periodic potential, causing scattering

$$v_{dp} = \mu_p E$$

hole mobility

mobility defines how well a carrier will move through a crystal at a given T and $N_{a,d}$
 units: $cm^2/V \cdot s$

$$J_{n, \text{drift}} = -en_0(-\mu_n \mathcal{E}) = e\mu_n n_0 \mathcal{E}$$

$$J_{p, \text{drift}} = e\mu_p p_0 \mathcal{E}$$

$$\star J_{\text{drift}} = e(\mu_n n_0 + \mu_p p_0) \mathcal{E} \quad \text{Total drift current density}$$

Mobility

→ one of the most quoted properties of a S.C.

Looking back at impact of \mathcal{E} -field on carriers:

$$F = m_{n,p}^* \frac{dv}{dt} = e\mathcal{E}$$

assume m^* and \mathcal{E} are constant

$$v = \frac{e\mathcal{E}t}{m_{n,p}^*}$$

Note on carrier motion: most is thermal (from $T > 0K$) and small \mathcal{E} -field just adds some directionality

$$v = \left(\frac{e\tau_{cp}}{m_p^*} \right) \mathcal{E}$$

→ mean time between scattering events/collisions

\star use a statistical model to determine impact of collision events and their frequency:

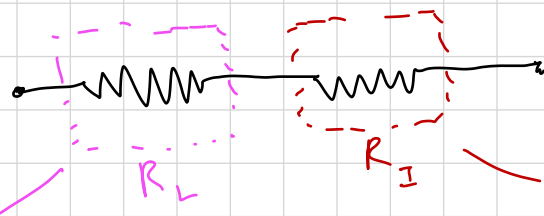
$$v = \mu_r \mathcal{E} \rightarrow$$

$$\mu_p = \frac{e\tau_{cp}}{m_p^*}$$

$$\mu_n = \frac{e\tau_{cn}}{m_n^*}$$

→ two scattering events degrade μ :

think about them as resistance added in path of current flow: (just an analogy)



lattice scattering

→ No doping dependence

→ Decreases with $\downarrow T$

impurity scattering

→ Increases with $\downarrow T$

→ Increases with $\uparrow N_a$ or $\uparrow N_d$

"total"

$$\text{mobility: } \frac{1}{\mu} = \frac{1}{\mu_L} + \frac{1}{\mu_I}$$

Conductivity σ

$$J_{\text{drift}} = e(\mu_n n_0 + \mu_p p_0) \mathcal{E} = \sigma \mathcal{E} \quad \star$$

$$\sigma = e(\mu_n n_0 + \mu_p p_0) \quad S/cm$$

Resistivity ρ

$$\rho = \frac{1}{\sigma} = \frac{1}{e(\mu_n n_0 + \mu_p p_0)} \quad \sim \text{cm}$$

Unique case (but happens frequently):

$$N_a \gg n_i, N_d = 0$$

$$\rightarrow \sigma \approx e \mu_p p_0 = e \mu_p N_a \quad \text{assuming complete ionization}$$

Velocity saturation

at low-to-moderate \mathcal{E} -fields, v_{drift} is linearly $\propto \mathcal{E}$

* \mathcal{E} -field does not substantially impact e^- energy but at higher \mathcal{E} -field it does lead to added scattering effects

$$\text{For holes: } v_d = \frac{\mu \mathcal{E}}{\left[1 + \left(\frac{\mu \mathcal{E}}{v_{\text{sat}}}\right)\right]} = \begin{cases} \mu \mathcal{E} & \dots \mathcal{E} \rightarrow 0 \text{ (small } \mathcal{E}) \\ v_{\text{sat}} & \dots \mathcal{E} \rightarrow \infty \text{ (large } \mathcal{E}) \end{cases}$$